

Search Notes

Application/Control No.

10/563,327

Examiner

TAN Q. NGUYEN

Applicant(s)/Patent under
Reexamination

IMAI, AKIRA

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	1,2,300 301,205 206,207 213	8/14/2008	TN
455	456.1		
340	435,436		
	903		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS SEARCH	8/15/2008	TN
EAST SEARCH	8/14/2008	TN